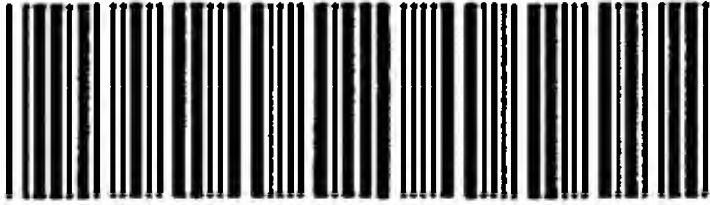


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/643,604	NASIELSKI ET AL.	
	Examiner	Art Unit	
	Quynh H. Nguyen	2614	

SEARCHED			
Class	Subclass	Date	Examiner
370	259	1/30/2008	QN
	352		
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455	414.1	1/30/08	QN
379	215.01	1/30/08	QN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Searched: East, USPGPub, USPAT, EPO, JPO	1/30/08	QN
Inventor searched in PALM	1/30/08	QN